

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination MIYACHI ET AL.	
		Examiner Sean P. Cullen, Ph.D.	Art Unit 1725	Page 1 of 1

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*	C	US-6,053,953 A	04-2000	Tomiyama et al.	29/623.1
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	L	US-			
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#### NON-PATENT DOCUMENTS

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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